

# 2SC1518

## Silicon NPN epitaxial planar type

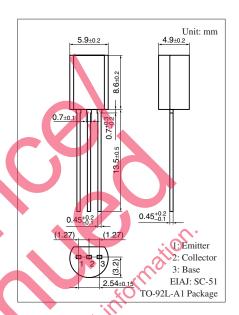
For high-frequency bias oscillation of tape recorders For DC-DC converter

#### ■ Features

- Low collector-emitter saturation voltage V<sub>CE(sat)</sub>
- Satisfactory operation performances and high efficiency with a lowvoltage power supply

### ■ Absolute Maximum Ratings $T_a = 25$ °C

| Parameter                             | Symbol           | Rating      | Unit |  |
|---------------------------------------|------------------|-------------|------|--|
| Collector-base voltage (Emitter open) | V <sub>CBO</sub> | 25          | V    |  |
| Collector-emitter voltage (Base open) | V <sub>CEO</sub> | 20          | V    |  |
| Emitter-base voltage (Collector open) | $V_{EBO}$        | 5           | V    |  |
| Collector current                     | $I_C$            | 1           | A    |  |
| Peak collector current                | $I_{CP}$         | 1.5         | A    |  |
| Collector power dissipation           | Pc               | 1           | W    |  |
| Junction temperature                  | T <sub>j</sub>   | 150         | °C   |  |
| Storage temperature                   | T <sub>stg</sub> | -55 to +150 | °C   |  |



## ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

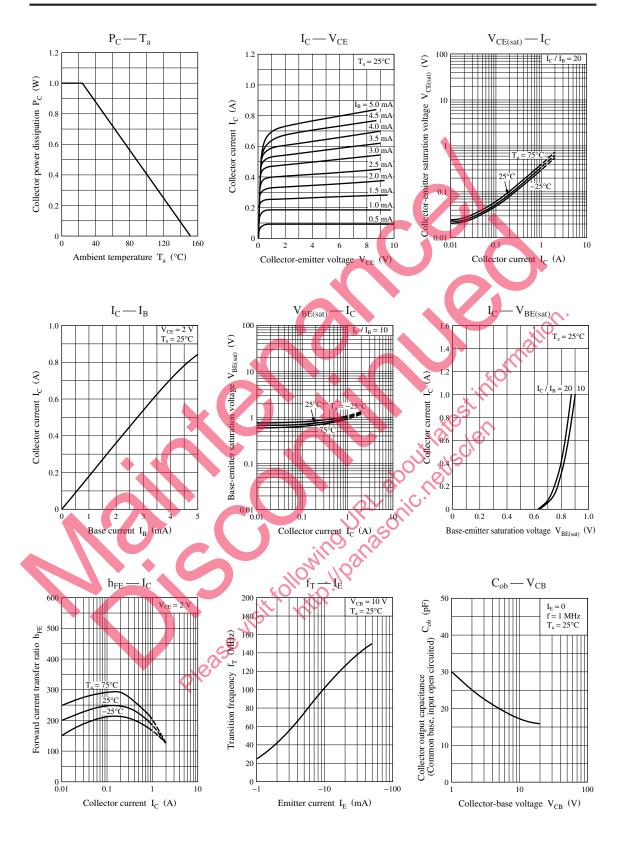
| Collector power dissipation                         | PC                   | 1 W   |     | 11. |     |      |  |  |  |  |
|---|----------------------|---|-----|-----|-----|------|--|--|--|--|
| Junction temperature T <sub>i</sub> 150 °C          |                      |   |     |     |     |      |  |  |  |  |
| Storage temperature T <sub>stg</sub> -55 to +150 °C |                      |   |     |     |     |      |  |  |  |  |
|   |                      |   |     |     |     |      |  |  |  |  |
| Parameter   | Symbol               | Conditions  | Min | Тур | Max | Unit |  |  |  |  |
| Collector-base voltage (Emitter open)               | $V_{CBO}$            | $I_{\rm C} = 10  \mu A, I_{\rm E} = 0$  | 25  |     |     | V    |  |  |  |  |
| Collector-emitter voltage (Base open)               | V <sub>CEO</sub>     | $V_{CEO}$ $I_C = 1 \text{ mA}$ $I_B = 0$  |     |     |     | V    |  |  |  |  |
| Emitter-base voltage (Collector open)               | V <sub>EBO</sub>     | $V_{\rm EBO}$ $I_{\rm E} = 10\mu$ A, $I_{\rm C} \neq 0$                         |     |     |     | V    |  |  |  |  |
| Collector-base cutoff current (Emitter open)        | $I_{CBO}$            | $I_{CBO}$ $V_{CB} = 25 \text{ V} \cdot I_{B} = 0$                               |     |     | 100 | nA   |  |  |  |  |
| Collector-emitter cutoff current (Base open)        | I <sub>CEO</sub>     | $I_{CEO}$ , $V_{CE} = 20$ V, $I_B = 0$  |     |     | 1   | μΑ   |  |  |  |  |
| Forward current transfer ratio                      | h <sub>FE1</sub> *   | $V_{CE} = 2 \text{ V}, I_{C} = 500 \text{ mA}$                                  | 90  |     | 330 |      |  |  |  |  |
|   | ch <sub>FE2</sub>    | $V_{CE} = 2 \text{ V}, I_{C} = 1 \text{ A}$                                     | 50  | 100 |     | _    |  |  |  |  |
| Collector-emitter saturation voltage                | V <sub>CE(sat)</sub> | $I_{\text{CE(sat)}}$ $I_{\text{C}} = 1 \text{ A}, I_{\text{B}} = 50 \text{ mA}$ |     |     | 0.5 | V    |  |  |  |  |
| Base-emitter saturation voltage                     | V <sub>BE(sat)</sub> | $I_{\rm C} = 500 \text{ mA}, I_{\rm B} = 50 \text{ mA}$                         |     |     | 1.2 | V    |  |  |  |  |
| Transition frequency                                | $f_T$                | $V_{CB} = 10 \text{ V}, I_E = -50 \text{ mA}, f = 200 \text{ MHz}$              |     | 150 |     | MHz  |  |  |  |  |
| Collector output capacitance                        | C <sub>ob</sub>      | $V_{CB} = 10 \text{ V}, I_{E} = 0, f = 1 \text{ MHz}$                           |     | 12  | 20  | pF   |  |  |  |  |
| (Common base, input open circuited)                 |                      |   |     |     |     |      |  |  |  |  |

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

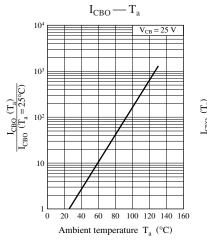
#### 2. \*: Rank classification

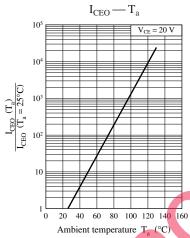
| Rank          | Q         | R          | S          |
|---------------|-----------|------------|------------|
| $h_{\rm FE1}$ | 90 to 155 | 130 to 220 | 185 to 330 |

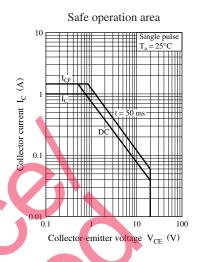
SJC00107BED Publication date: November 2002



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